π^0 Lifetime Analysis for ${}^{12}C$ and ${}^{208}Pb$

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PrimEx Collaboration





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Recent Work

- Refined yield fit algorithm to use the predicted plus the fit interference phase angle.
- Performed yield fits with Sergey using Tulio's most recent incoherent cross sections.
- Incorporated pi0 background from coherent and incoherent omega production.
- Evaluated $\Gamma_{\gamma\gamma}$ for 5 different yields (with varying bkgd corrections):
 - \rightarrow Standard Bkgd Correction (sb)

 - $\begin{array}{l} \rightarrow & \text{No Bkgd Correction (nb)} \\ \rightarrow & \text{Omega Bkgd Correction (ob)} \\ \rightarrow & \text{Omega Bkgd Correction +20\% (ob+)} \\ \rightarrow & \text{Omega Bkgd Correction -20\% (ob-)} \end{array}$



Sample Yield Fit for ¹²C: SI (left) and TI (right)





Sample Yield Fit for ¹²C: SI (left) and S2I (right)





Sample Yield Fit for ²⁰⁸Pb: TA (left) and SA (right)









Preliminary Result Summary

target	Γγγ	fitting (stat) error	model error	syst error	total e	rror
C: av	7.90	0.15(1.9%)	0.09(1.1%)	0.18(2.3%)	0.25(3.	2%)
Pb:av	8.13	0.17(2.1%)	0.07(0.9%)	0.19(2.3%)	0.26(3.	2%)
Pb+C av	8.01	0.12(1.5%)	0.15(1.9%)	0.18(2.3%)	0.26(3.	2%)

Table 1: Average extracted value of $\Gamma(\pi^0 \to \gamma \gamma)$ and the errors in eV(%). The averages were taken over all of the fits. The total error adds in quadrature the fitting, model, and the systematic error.